

The Qualification tests were performed per standard test conditions (JEDED, AEC-101, MIL-STD-883).

Stress	Abbv.	Ref.	Conditions	Duration/Acceptance	Lot A	Lot B	Lot C
Electrical Parameter Assessment	ED	JESD86	Datasheet	Per datasheet	All	All	All
High Temperature Reverse Bias	HTRB	JESD22-A108 JESD85	80% of BVDS(max)	1008 hr/0 fail	0/45	0/45	0/45
High Temperature Gate Bias	HTGB	JESD22-A108 JESD85	80% OF BVgs(max)	1008 hr / 0 fail	0/45	0/45	0/45
Temperature Cycling	TC	JESD22-A104	-40°C to +125°C	1000 cycles/0 fail	0/45	0/45	0/45
Temperature/Humidity (Unbiased)	UHASt	JESD22-A118	-130°C, 80% RH	96 hours / 0 fail	0/45	0/45	0/45
Thermal Resistance Measurements Avg & Pulsed	ØJC	JESD24-3	data sheet operating conditions	Characterize device	0/5	0/5	0/5
Solderability	SD	JESD22-B102E	Per std	0 fail	0/15		
Resistance to Solder Heat	RSH	JESD22-B106C	Per std	0 fail	0/30		
Variable Vibration Frequency	VVF	JESD22-B103	20-2000 Hz Peak force = 20g	4 min w/ 4 travels per axis / 0 fail	0/5		
Mechanical Shock	MS	JESD22-B104	Accel = 1500 g Duration = 0.5 msec	5 times in both directions of 3 axis 6 directions total 0 fail	0/5		
Constant Acceleration	CA	MIL-STD-833-2001	10,000 g	Y1 Direction	0/6		

Note: Sample sizes were established based on the Military Standards for Lot Tolerance Percent Defective (LTPD) recommendations (5% level).